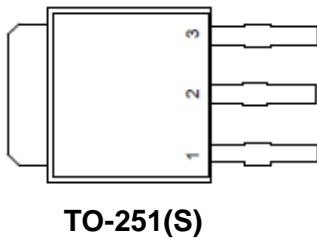


# P1504EIS

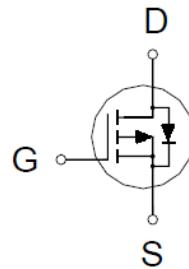
## P-Channel Enhancement Mode MOSFET

### PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
-40V	15mΩ @ $V_{GS} = -10V$	-38A



100%  $R_g$  tested  
100% UIS tested



### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	$V_{DS}$	-40	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current	$I_D$	-38	A
		-24	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	-150	
Avalanche Current	$I_{AS}$	-44	
Avalanche Energy	$E_{AS}$	96.8	mJ
Power Dissipation	$P_D$	34	W
		14	
Operating Junction & Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		75	°C / W
Junction-to-Case	$R_{\theta JC}$		3.6	

<sup>1</sup>Pulse width limited by maximum junction temperature.



# P1504EIS

## P-Channel Enhancement Mode MOSFET

### ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

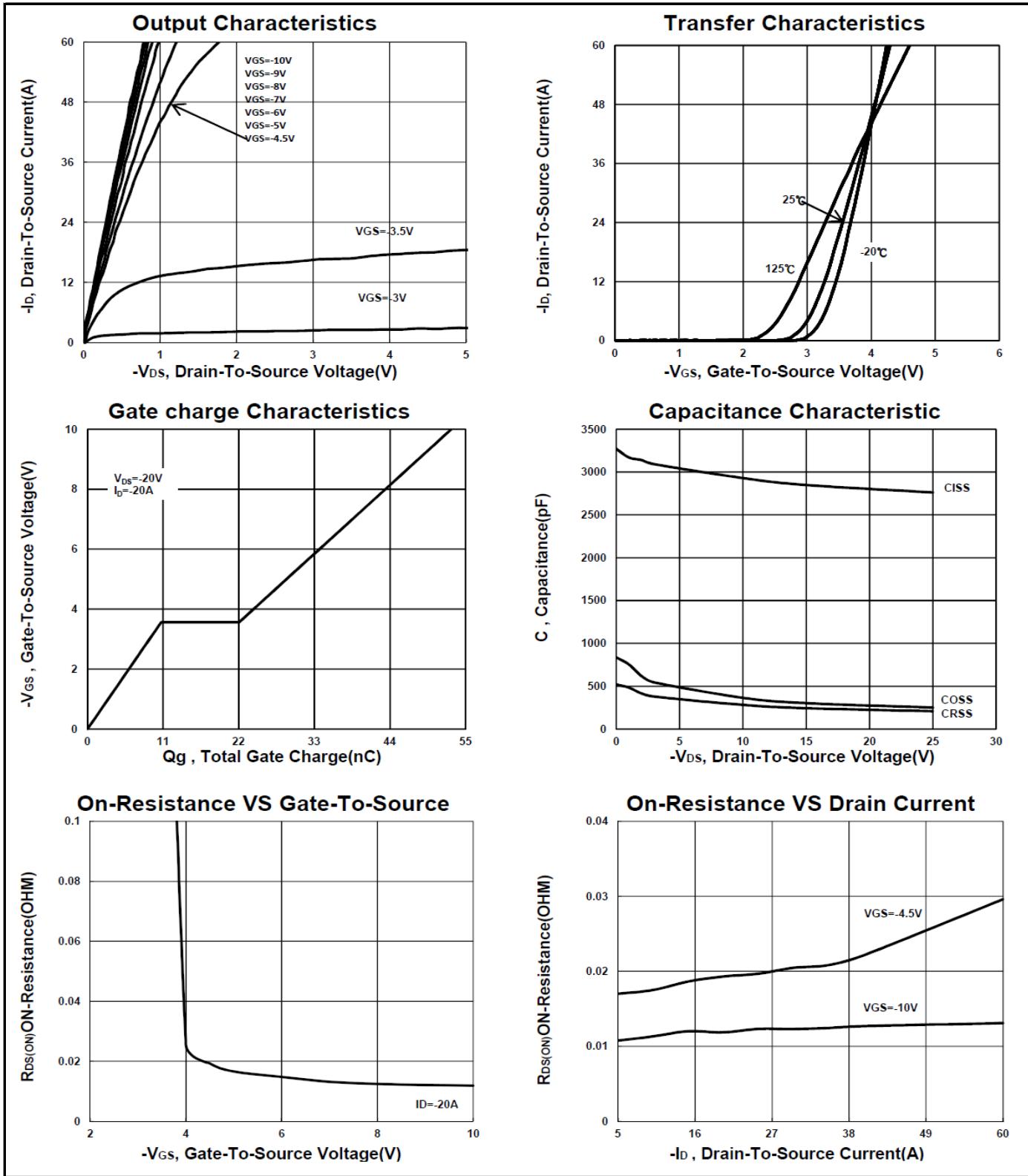
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	-40			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	-1.5	-2.2	-3	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			$\pm 100$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = -32\text{V}, V_{\text{GS}} = 0\text{V}$		1		$\mu\text{A}$
		$V_{\text{DS}} = -30\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$		10		
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -4.5\text{V}, I_D = -15\text{A}$		20	29	$\text{m}\Omega$
		$V_{\text{GS}} = -10\text{V}, I_D = -20\text{A}$		12	15	
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = -5\text{V}, I_D = -20\text{A}$		53		S
On-State Drain Current <sup>1</sup>	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = -5\text{V}, V_{\text{GS}} = -10\text{V}$	-150			A
<b>DYNAMIC</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -20\text{V}, f = 1\text{MHz}$		2870		pF
Output Capacitance	$C_{\text{oss}}$			273		
Reverse Transfer Capacitance	$C_{\text{rss}}$			238		
Gate Resistance	$R_g$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		4.4		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, V_{\text{GS}} = -10\text{V}, I_D = -20\text{A}$		55		nC
Gate-Source Charge <sup>2</sup>	$Q_{\text{gs}}$			12		
Gate-Drain Charge <sup>2</sup>	$Q_{\text{gd}}$			15		
Turn-On Delay Time <sup>2</sup>	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = -20\text{V}, I_D \approx -20\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GEN}} = 6\Omega$		13		nS
Rise Time <sup>2</sup>	$t_r$			31		
Turn-Off Delay Time <sup>2</sup>	$t_{\text{d}(\text{off})}$			72		
Fall Time <sup>2</sup>	$t_f$			40		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				-38	A
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = -20\text{A}, V_{\text{GS}} = 0\text{V}$			-1.3	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = -20\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		22		nS
Reverse Recovery Charge	$Q_{\text{rr}}$			14		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\text{ }\mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

<sup>2</sup>Independent of operating temperature.

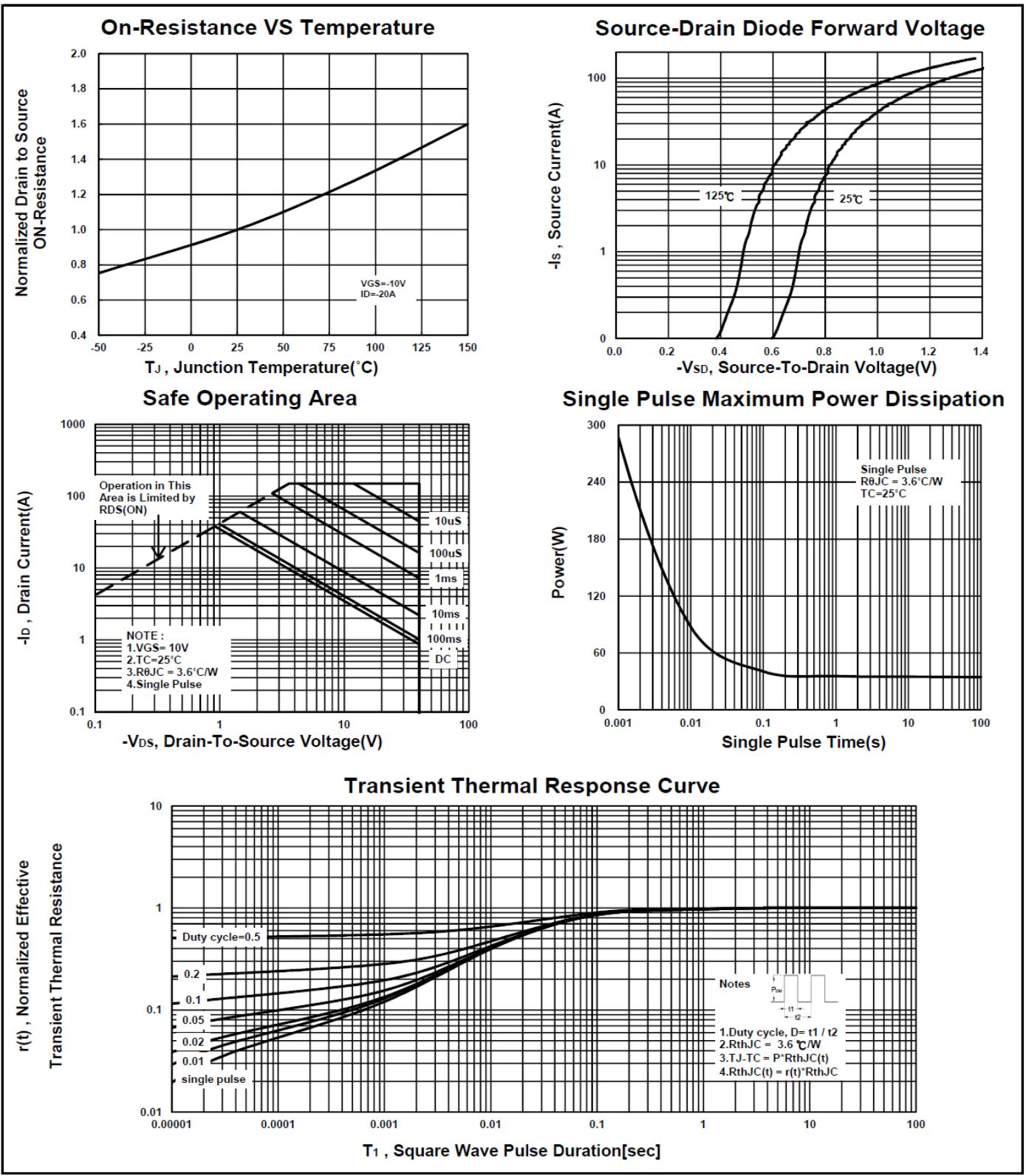
## P1504EIS

### P-Channel Enhancement Mode MOSFET



# P1504EIS

## P-Channel Enhancement Mode MOSFET



# P1504EIS

## P-Channel Enhancement Mode MOSFET

### Package Dimension

#### TO-251 (S) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	6.3	6.6	6.8	H	2.1	2.3	2.5
B	4.8	5.3	5.5	J	0.4	0.5	0.6
C	6.7		7.57	K	0.35	0.5	0.65
D	3	3.5	4.5	L	0.9		1.5
E		2.3		M	5.3		6.22
F	0.5		1.12	N	1.4	1.6	2.1
G	0.4		0.89				

